### INTEGRATED CIRCUITS

# DATA SHEET

## 74ABT16821A 74ABTH16821A

20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

Product specification Supersedes data of 1995 Sep 28 IC23 Data Handbook





## 20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

### 74ABT16821A 74ABTH16821A

#### **FEATURES**

- 20-bit positive-edge triggered register
- Multiple V<sub>CC</sub> and GND pins minimize switching noise
- Live insertion/extraction permitted
- Power-up reset
- Power-up 3-State
- 74ABTH16821A incorporates bus-hold data inputs which eliminate the need for external pull-up resistors to hold unused inputs
- Output capability: +64mA/-32mA
- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model

#### **DESCRIPTION**

The 74ABT16821A high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT16821A has two 10-bit, edge triggered registers, with each register coupled to a 3-State output buffer. The two sections of each register are controlled independently by the clock (nCP) and Output Enable (nOE) control gates.

Each register is fully edge triggered. The state of each D input, one set-up time before the Low-to-High clock transition, is transferred to the corresponding flip-flop's Q output.

The 3-State output buffers are designed to drive heavily loaded 3-State buses, MOS memories, or MOS microprocessors.

The active Low Output Enable ( $n\overline{OE}$ ) controls all ten 3-State buffers independent of the register operation. When  $n\overline{OE}$  is Low, the data in the register appears at the outputs. When  $n\overline{OE}$  is High, the outputs are in high impedance "off" state, which means they will neither drive nor load the bus.

Two options are available, 74ABT16821A which does not have the bus-hold feature and 74ABTH16821A which incorporates the bus-hold feature.

#### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	CONDITIONS T <sub>amb</sub> = 25°C; GND = 0V	TYPICAL	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nCP to nQx	C <sub>L</sub> = 50pF; V <sub>CC</sub> = 5V	2.4 2.0	ns
C <sub>IN</sub>	Input capacitance	$V_I = 0V$ or $V_{CC}$	3	pF
C <sub>OUT</sub>	Output capacitance	$V_O = 0V$ or $V_{CC}$ ; 3-State	7	pF
I <sub>CCZ</sub>	Outcocont gupply gurrent	Outputs disabled; V <sub>CC</sub> = 5.5V	500	μΑ
I <sub>CCL</sub>	Quiescent supply current	Outputs LOW; V <sub>CC</sub> = 5.5V	10	mA

#### **ORDERING INFORMATION**

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ABT16821A DL	BT16821A DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABT16821A DGG	BT16821A DGG	SOT364-1
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ABTH16821A DL	BH16821A DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABTH16821A DGG	BH16821A DGG	SOT364-1

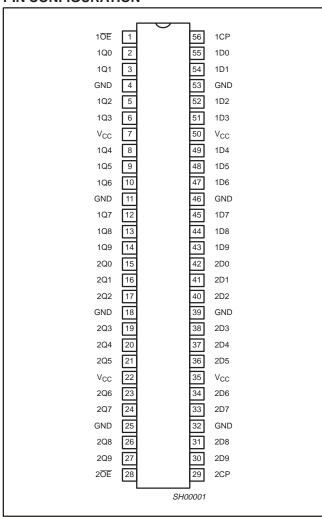
#### **PIN DESCRIPTION**

PIN NUMBER	SYMBOL	FUNCTION
55, 54, 52, 51, 49, 48, 47, 45, 44, 43, 42, 41, 40, 38, 37, 36, 34, 33, 31, 30	1D0 - 1D9 2D0 - 2D9	Data inputs
2, 3, 5, 6, 8, 9, 10, 12, 13, 14, 15, 16, 17, 19, 20, 21, 23, 24, 26, 27	1Q0 - 1Q9 2Q0 - 2Q9	Data outputs
1, 28	1 <del>0E</del> , 2 <del>0E</del>	Output enable inputs (active-Low)
56, 29	1CP, 2CP	Clock pulse inputs (active rising edge)
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0V)
7, 22, 35, 50	V <sub>CC</sub>	Positive supply voltage

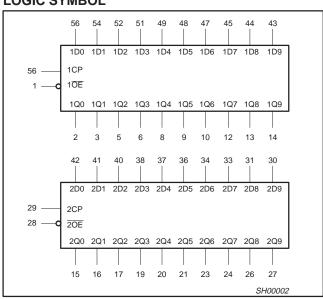
## 20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

### 74ABT16821A 74ABTH16821A

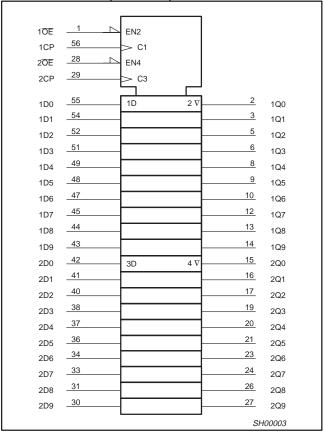
#### PIN CONFIGURATION



#### LOGIC SYMBOL



#### LOGIC SYMBOL (IEEE/IEC)



#### **FUNCTION TABLE**

ı	INPUTS		INTERNAL	OUTPUTS	OPERATING
nOE	nCP	nDx	REGISTER	nQ0 - nQ9	MODE
L L	$\uparrow$	l h	L H	L H	Load and read register
L	1	Х	NC	NC	Hold
H H	<b>↑</b>	X Dn	NC Dn	Z Z	Disable outputs

H = High voltage level

n = High voltage level one set-up time prior to the Low-to-High clock transition

L = Low voltage level

= Low voltage level one set-up time prior to the Low-to-High clock transition

NC= No change X = Don't care

Z = High impedance "off" state = Low to High clock transition

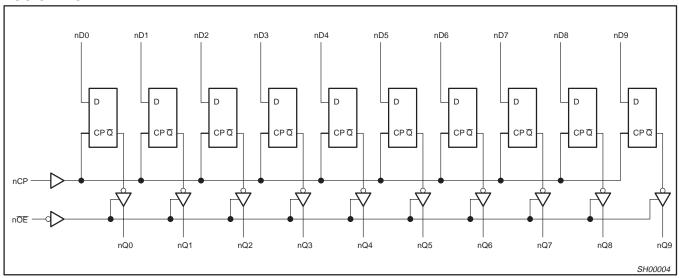
↑ = Low to Figh clock transition ↑ = Not a Low-to-High clock transition

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## 20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

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#### LOGIC DIAGRAM



#### ABSOLUTE MAXIMUM RATINGS1, 2

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V <sub>CC</sub>	DC supply voltage		-0.5 to +7.0	V
I <sub>IK</sub>	DC input diode current	V <sub>1</sub> < 0	-18	mA
VI	DC input voltage <sup>3</sup>		-1.2 to +7.0	V
I <sub>OK</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>OUT</sub>	DC output voltage <sup>3</sup>	Output in Off or High state	-0.5 to +5.5	V
1	DC output current	Output in Low state	128	mA
Гоит	De output current	Output in High state	-64	IIIA
T <sub>stg</sub>	Storage temperature range		-65 to 150	°C

#### NOTES:

- 1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- 2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
- 3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIM	UNIT	
		MIN	MAX	
V <sub>CC</sub>	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V <sub>CC</sub>	V
$V_{IH}$	High-level input voltage	2.0		V
$V_{IL}$	Low-level Input voltage		0.8	V
I <sub>OH</sub>	High-level output current		-32	mA
$I_{OL}$	Low-level output current		64	mA
Δt/Δν	Input transition rise or fall rate	0	10	ns/V
T <sub>amb</sub>	Operating free-air temperature range	-40	+85	°C

### 20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

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#### DC ELECTRICAL CHARACTERISTICS

				LIMITS					
SYMBOL	BOL PARAMETER TEST CONDITIONS			Tai	<sub>nb</sub> = +25	5°C	T <sub>amb</sub> = -40°C to +85°C		UNIT
						Max	Min	Max	
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = 4.5V; I <sub>IK</sub> = -18mA			-0.9	-1.2		-1.2	V
		$V_{CC} = 4.5V; I_{OH} = -3mA; V_I = V_{IL} c$	or V <sub>IH</sub>	2.5	2.9		2.5		V
$V_{OH}$	High-level output voltage	$V_{CC} = 5.0V; I_{OH} = -3mA; V_I = V_{IL} c$	or V <sub>IH</sub>	3.0	3.4		3.0		V
		$V_{CC} = 4.5V; I_{OH} = -32mA; V_{I} = V_{IL}$	or V <sub>IH</sub>	2.0	2.4		2.0		V
$V_{OL}$	Low-level output voltage	$V_{CC} = 4.5V; I_{OL} = 64mA; V_{I} = V_{IL} c$	or V <sub>IH</sub>		0.36	0.55		0.55	V
$V_{RST}$	Power-up output voltage <sup>3</sup>	$V_{CC} = 5.5V; I_{O} = 1mA; V_{I} = GND c$	or V <sub>CC</sub>		0.13	0.55		0.55	V
I <sub>1</sub>	Input leakage current	$V_{CC} = 5.5V$ ; $V_I = V_{CC}$ or GND			±0.01	±1.0		±1.0	μΑ
		$V_{CC} = 5.5V$ ; $V_I = V_{CC}$ or GND	Control pins		±0.01	±1		±1	μΑ
II	Input leakage current 74ABTH16821A	$V_{CC} = 5.5V; V_{I} = V_{CC}$			0.01	1		1	μΑ
		V <sub>CC</sub> = 5.5V; V <sub>I</sub> = 0	Data pins		-1	-3		-5	μΑ
	_	V <sub>CC</sub> = 4.5V; V <sub>I</sub> = 0.8V	$V_{CC} = 4.5V; V_I = 0.8V$				35		
$I_{HOLD}$	Bus Hold current inputs <sup>5</sup> 74ABTH16821A	V <sub>CC</sub> = 4.5V; V <sub>I</sub> = 2.0V		<del>-</del> 75			-75		μΑ
		$V_{CC} = 5.5V$ ; $V_I = 0$ to 5.5V		±800					
I <sub>OFF</sub>	Power-off leakage current	$V_{CC} = 0.0V; V_{O} \text{ or } V_{I} \le 4.5V$			±5.0	±100		±100	μΑ
I <sub>PU/PD</sub>	Power-up/down 3-State output current <sup>4</sup>	$V_{\underline{CC}}$ = 2.1V; $V_{\underline{O}}$ = 0.5V; $V_{\underline{I}}$ = GND $V_{\underline{OE}}$ = Don't care	or V <sub>CC</sub> ;		±5.0	±50		±50	μА
I <sub>OZH</sub>	3-State output High current	$V_{CC} = 5.5V; V_O = 2.7V; V_I = V_{IL} \text{ or}$	V <sub>IH</sub>		1.0	10		10	μΑ
I <sub>OZL</sub>	3-State output Low current	$V_{CC} = 5.5V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or }$	V <sub>IH</sub>		-1.0	-10		-10	μΑ
I <sub>CEX</sub>	Output High leakage current	$V_{CC} = 5.5V; V_O = 5.5V; V_I = GND$	or V <sub>CC</sub>		5.0	50		50	μА
IO	Output current <sup>1</sup>	V <sub>CC</sub> = 5.5V; V <sub>O</sub> = 2.5V		<b>-</b> 50	-90	-180	<b>-</b> 50	-180	mA
I <sub>CCH</sub>		$V_{CC}$ = 5.5V; Outputs High, $V_{I}$ = GND or $V_{CC}$			0.5	1		1	mA
I <sub>CCL</sub>	Quiescent supply current	$V_{CC}$ = 5.5V; Outputs Low, $V_I$ = GND or $V_{CC}$			10	19		19	mA
I <sub>CCZ</sub>	]	V <sub>CC</sub> = 5.5V; Outputs 3-State; V <sub>I</sub> =	GND or V <sub>CC</sub>		0.5	1		1	mA
Δl <sub>CC</sub>	Additional supply current per input pin <sup>2</sup>	V <sub>CC</sub> = 5.5V; one input at 3.4V, other V <sub>CC</sub> or GND	er inputs at		0.25	1.5		1.5	mA

#### NOTES:

- 1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
- 2. This is the increase in supply current for each input at 3.4V.
- For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.
  This parameter is valid for any V<sub>CC</sub> between 0V and 2.1V with a transition time of up to 10msec. From V<sub>CC</sub> = 2.1V to V<sub>CC</sub> = 5V a transition time of up to 100µsec is permitted.
- 5. This is the bus hold overdrive current required to force the input to the opposite logic state.

## 20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

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#### **AC CHARACTERISTICS**

GND = 0V,  $t_R = t_F = 2.5$ ns,  $C_L = 50$ pF,  $R_L = 500\Omega$ 

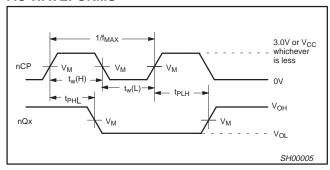
			LIMITS					
SYMBOL PARAMETER		WAVEFORM	T <sub>amb</sub> = +25°C V <sub>CC</sub> = +5.0V			T <sub>amb</sub> = -40 to +85°C V <sub>CC</sub> = +5.0V ±0.5V		UNIT
			MIN	TYP	MAX	MIN	MAX	
f <sub>MAX</sub>	Maximum clock frequency	1	160	250		160		MHz
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nCP to nQx	1	1.3 1.1	2.4 2.0	3.3 2.6	1.3 1.1	3.7 3.0	ns
t <sub>PZH</sub>	Output enable time to High and Low level	3 4	1.4 1.2	2.5 2.3	3.3 3.0	1.4 1.2	4.1 3.7	ns
t <sub>PHZ</sub>	Output disable time from High and Low level	3 4	1.6 1.3	3.2 2.3	4.1 3.1	1.6 1.3	4.8 3.3	ns

#### **AC SETUP REQUIREMENTS**

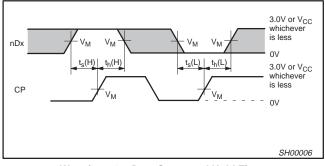
GND = 0V,  $t_R = t_F$  = 2.5ns,  $C_L$  = 50pF,  $R_L$  = 500 $\Omega$ 

				LIM	ITS		
SYMBOL	PARAMETER	WAVEFORM	T <sub>amb</sub> = V <sub>CC</sub> =	: +25°C : +5.0V	T <sub>amb</sub> = -40 V <sub>CC</sub> = +5	0 to +85°C .0V ±0.5V	UNIT
			MIN	TYP	MIN	MAX	
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time, High or Low nDx to nCP	2	1.8 1.8	1.2 -0.9	1.8 1.8		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, High or Low nDx to nCP	2	1.0 1.0	0.8 -1.0	1.0 1.0		ns
t <sub>w</sub> (H) t <sub>w</sub> (L)	nCP pulse width High or Low	1	2.5 2.5	0.8 1.0	2.5 2.5		ns

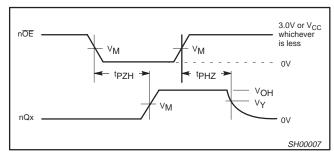
#### **AC WAVEFORMS**



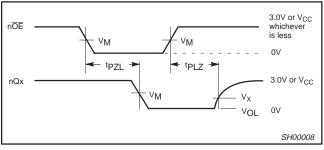
Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock frequency



Waveform 2. Data Setup and Hold Times



Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level



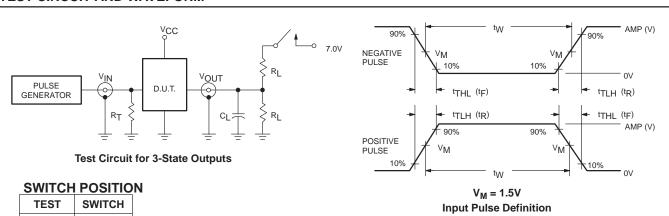
Waveform 4. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

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## 20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

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### **TEST CIRCUIT AND WAVEFORM**



TEST	SWITCH
t <sub>PLZ</sub>	closed
$t_{PZL}$	closed
All other	open

#### **DEFINITIONS**

R<sub>L</sub> = Load resistor; see AC CHARACTERISTICS for value.

 $C_L = Load$  capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

 $R_T = Termination resistance should be equal to <math>Z_{OUT}$  of pulse generators.

EA MILV	INPUT PULSE REQUIREMENTS							
FAMILY	Amplitude	Rep. Rate	t <sub>W</sub>	t <sub>R</sub>	t <sub>F</sub>			
74ABT/H16	3.0V	1MHz	500ns	2.5ns	2.5ns			

SA00018

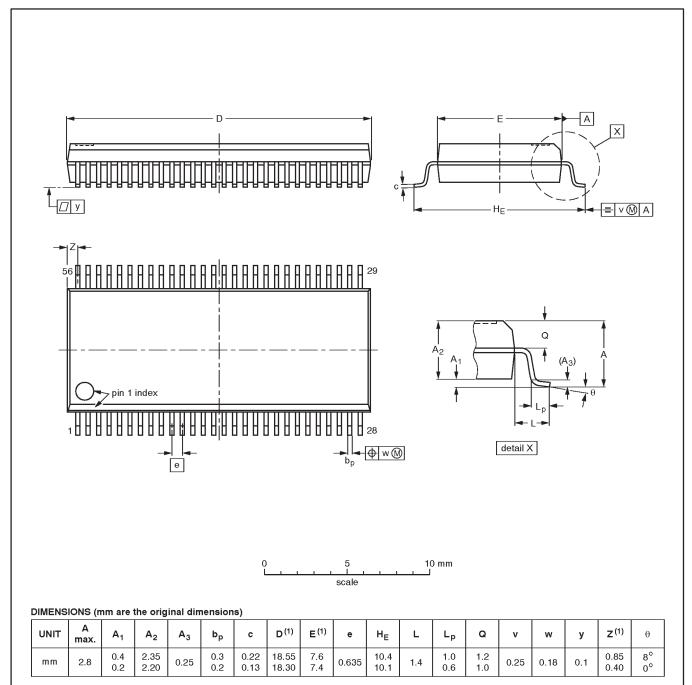
Philips Semiconductors Preliminary specification

20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

74ABT16821A 74ABTH16821A

### SSOP56: plastic shrink small outline package; 56 leads; body width 7.5 mm

SOT371-1



#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE	REFERENCES			REFERENCES		ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT371-1		MO-118AB				<del>93-11-02</del> 95-02-04

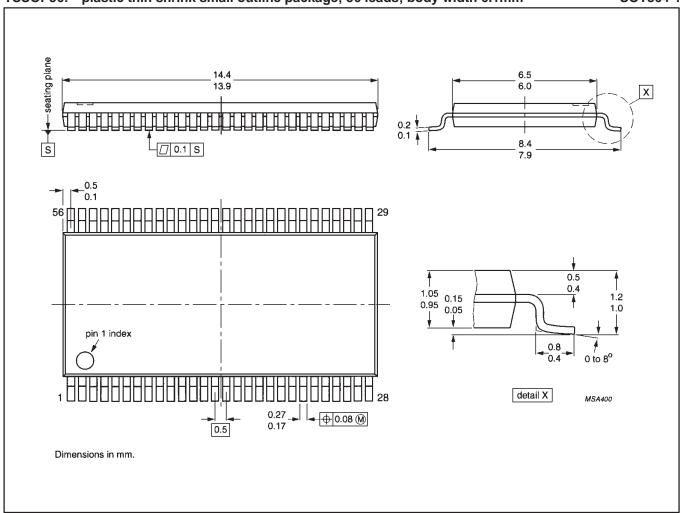
Philips Semiconductors Preliminary specification

20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

74ABT16821A 74ABTH16821A

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1mm

SOT364-1



20-bit bus-interface D-type flip-flop; positive-edge trigger (3-State)

74ABT16821A 74ABTH16821A

#### Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

<sup>[1]</sup> Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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